

2/19/03

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219517US-2S DIV		SERIAL NO. 10/076,325	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO et al.			
				FILING DATE February 19, 2002		GROUP 2615-2616	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
HN	AA	5,712,947	27 Jan 1998	Oguro et al.			
HN	AB	6,148,138	14 Nov 2000	Sawabe et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
HN	AO	JP 5-158778	25 Jun 1993	Japan	x		
HN	AP	JP 5-165935	2 July 1993	Japan	x		
HN	AQ	JP 7-143429	2 Jun 1995	Japan (with Statement of Relevancy)			x
HN	AR	JP 8-205014	9 Aug 1996	Japan	x		
HN	AS	JP 9-182013	11 July 1997	Japan	x		
HN	AT	JP 11-136613	21 May 1999	Japan	x		
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
HN	AW	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD00201476 (with English Translation).					
HN	AX	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD09804370 (with English Translation).					
HN	AY	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD09904198 (with English Translation).					
	AZ						
Examiner H. H. H. H.					Date Considered 9/16/04		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

I:\atty\Sam\219517\Petition Make Special.1449.wpd

BEST AVAILABLE COPY

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219517US2S DIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT			
				FILING DATE Herewith		GROUP 2616	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>RM</i>	AA	5,687,160	11/97	Aotake et al.	—	—	
<i>RM</i>	AB	5,731,852	03/98	Lee	—	—	
<i>RM</i>	AC	6,185,365	02/01	Murase et al.	—	—	
<i>RM</i>	AD	6,067,400	05/00	Saeki et al.	—	—	
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>RM</i>	AO	7-143429	06-02-95	JAPAN			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>Thuy Nguyen</i>					Date Considered <i>9/16/04</i>		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

 11046 U.S. PTO
 10/076325
 02/19/02

BEST AVAILABLE COPY

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
219517US2SDIVSERIAL NO.
10/076,325

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Hideo ANDO, et al.FILING DATE
February 19, 2002GROUP
2613 2616RECEIVED
OCT 11 2002
Technology Center 2600

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HN</i>	AA	6,385,389 B1	07May02	<u>Maruyama et al.</u>			
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>HN</i>	AG	EP 1 065 665 A1	03Jan01	European Patent Office (in English)		
<i>HN</i>	AH	JP 5-81787	02Apr93	JAPAN	x	
<i>HN</i>	AI	JP 7-143429	02Jun95	JAPAN	x	
<i>HN</i>	AJ	JP 8-106721	23Apr96	JAPAN	x	
<i>HN</i>	AK	JP 9-259539	03Oct97	JAPAN	x	
<i>HN</i>	AL	JP 11-215471	6Aug99	JAPAN (corresponding U.S. Patent no. 6,385,389 B1 <u>Maruyama, et al.</u>)		x
<i>HN</i>	AM	JP 11-238362	31Aug99	JAPAN (corresponding European Patent No. EP 1 065 665, <u>ANDO, et al.</u>)		x
	AN					
	AO					
	AP					
	AQ					
	AR					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>HN</i>	AS	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310033 (with English translation)
<i>HN</i>	AT	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310034 (with English translation)
<i>HN</i>	AU	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310035 (with English translation)
<i>HN</i>	AV	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310036 (with English translation)
<i>HN</i>	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310037 (with English translation)
	AX	

☐ Additional References sheet(s) attached

Examiner

Greg R. Ruggie

Date Considered

9/16/04

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

I:\ATTY\CHY219517us\219517PTO-1449.doc

BEST AVAILABLE COPY